Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2	semiconductor ADJ device with wait ADJ time	USPAT	OR	OFF	2004/05/24 16:02
S2	37	semiconductor with wait ADJ time	USPAT	OR	OFF	2004/05/24 16:02
S3	109	semiconductor with wait$3 ADJ time	USPAT	OR	ON	2004/05/24 16:02
S4	109	semiconductor with wait$3 ADJ timè	USPAT	OR	ON	2004/05/24 16:04
S5	593	semiconductor ADJ device AND wait$3 ADJ time	USPAT	OR	ON	2004/05/24 16:04
S6	6	semiconductor ADJ device AND wait$3 ADJ time with elapse	USPAT	OR	ON	2004/05/24 16:07
S7	0	714/815.ccls. and semiconductor ADJ device AND wait$3 ADJ time with elapse	USPAT	OR	ON	2004/05/24 16:08
S8	1	714/815.ccls. and semiconductor ADJ device AND wait$3 ADJ time	USPAT	OR	ON	2004/05/24 16:08
S9	196	714/815.ccls.	USPAT	OR	ON	2004/05/24 16:09
S10	40	714/815.ccls. and (wait or delay) adj tim$3	USPAT	OR	ON	2004/05/24 16:35
S11	5	714/815.ccls. and (wait or delay) adj tim$3 with measur$5	USPAT	OR	ON	2004/05/24 16:37
S12	1	714/815.ccls. and (wait or idle) adj tim$3 with measur$5	USPAT	OR	ON	2004/05/24 16:37
S13	6	714/815.ccls. and wait adj tim$3	USPAT	OR	ON	2004/05/24 16:41
S14	287	"714"/$.ccls. and wait adj tim$3	USPAT	OR	ON	2004/05/24 16:41
S15	287	"714"/$.ccls. and wait adj tim$3	USPAT	OR	ON	2004/05/24 16:44
S16	3	"714"/$.ccls. and wait adj tim$3 with measur$5	USPAT	OR	ON	2004/05/24 16:44
S17	27	"714"/$.ccls. and wait adj tim$3 with test$3	USPAT	OR	ON	2004/05/24 16:47
S18	0	"714"/$.ccls. and taet adj pattern and wait adj tim$3	USPAT	OR	ON	2004/05/24 16:47
S19	19	"714"/$.ccls. and test adj pattern and wait adj tim$3	USPAT	OR	ON	2004/05/24 16:57
S20	188	"714"/$.ccls. and test adj pattern and wait$ with tim$3	USPAT	OR	ON	2004/05/24 16:58
S21	25	"714"/$.ccls. and test adj pattern and wait$ with tim$3 and device adj under adj test	USPAT	OR	ON	2004/05/24 17:50
S22	160	"714"/$.ccls. and test adj pattern and (wait$ or delay) with tim$3 and device adj under adj test	USPAT	OR	ON	2004/05/24 18:11

S23	31	"714"/$.ccls. and test adj pattern and (wait$ or delay) with tim$3 with compar$4 and device adj under adj test	USPAT	OR	ON	2004/05/24 18:10
S24	0	"714"/$.ccls. and test adj pattern and variable ADJ time ADJ delay and device adj under adj test	USPAT	OR	ON	2004/05/24 18:12
S25	1	"714"/$.ccls. and test adj pattern and variable ADJ time ADJ delay	USPAT	OR	ON	2004/05/24 18:13
S26	0	"714"/$.ccls. and test adj pattern and variable ADJ wait$3 ADJ time	USPAT	OR	ON	2004/05/24 18:13
S27	0	"714"/$.ccls. and test adj pattern and adjustable with wait$3 ADJ time	USPAT	OR	ON	2004/05/24 18:13
S28	0	"714"/$.ccls. and test adj pattern and adjust$3 with wait$3 adj (tim$3 or period)	USPAT	OR	ON	2004/05/24 18:14
S29	6	"714"/$.ccls. and test adj pattern with wait$3 adj (tim$3 or period)	USPAT	OR	ON	2004/05/24 18:16
S30	17	"714"/$.ccls. and test adj pattern with wait$3 with (tim$3 or period)	USPAT	OR	ON	2004/05/24 18:28
S31	0	"20020100000"	USPAT	OR	OFF	2004/05/24 18:28
S32	1	"20020100000"	US-PGPUB; USPAT	OR	OFF	2005/01/05 11:18
S33	383	TOSHIBA.as. and wait$3 adj tim$3	USPAT	OR	ON	2004/05/24 18:43
S34	28175	TOSHIBA.as. and wait$3 adj tim$3 and test adj pattern and deviceADJ under adj test	USPAT	OR	ON	2004/05/24 18:42
S35	0	TOSHIBA.as. and wait$3 adj tim$3 and test adj pattern and device ADJ under adj test	USPAT	OR	ON	2004/05/24 18:43
S36	1	TOSHIBA.as. and wait$3 adj tim$3 and device ADJ under adj test	USPAT	OR	ON	2004/05/24 18:43
S37	0	TOSHIBA.as. and wait$3 adj tim$3 with semiconductor adj test$3	USPAT	OR	ON	2004/05/24 18:44
S38	0	TOSHIBA.as. and wait$3 adj tim$3 and semiconductor adj test$3	USPAT	OR	ON	2004/05/24 18:46
S39	1	JP08247817	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/05/25 07:50
S40	1	JP08247817	USPAT; EPO; JPO; DERWENT	OR	OFF	2004/05/25 07:50
S41	1	measurement with adjust$4 with operating with speed and TESTING with SEMICONDUCTOR near DEVICE	USPAT	OR	OFF	2004/05/25 07:52

S42	1	measurement with adjust$4 with speed and TESTING with SEMICONDUCTOR near DEVICE	USPAT	OR	OFF	2004/05/25 07:53
S43	19	adjust$4 with speed and TESTING with SEMICONDUCTOR near DEVICE	USPAT	OR	OFF	2004/05/25 07:57
S44	36	adjust$4 with time with delay and TESTING with SEMICONDUCTOR near DEVICE	USPAT	OR	OFF	2005/01/05 12:53
S45	34	714/815.ccls. and (wait or delay) adj time	USPAT	OR	ON	2005/01/05 12:52
S58	1	US-6263463-$.DID.	USPAT	OR	OFF	2005/01/05 11:18
S59	5	"6263463"	USPAT	OR	OFF	2005/01/05 11:20
S60	34	714/815.ccls. and (wait or delay) adj time	USPAT	OR	ON	2005/01/05 12:52
S61	110	714/724.ccls. and (wait or delay) adj time	USPAT	OR	ON	2005/01/05 12:52
S62	44	adjust$4 with time with delay and TESTING with SEMICONDUCTOR near DEVICE	USPAT	OR	OFF	2005/01/05 12:53